

#### **Description**

The AP3134AL uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **General Features**

V<sub>DS</sub> =20V I<sub>D</sub> =0.9A

 $R_{DS(ON)} < 250 m\Omega$  @  $V_{GS}$ =4.5V (Type: 135 $m\Omega$ )

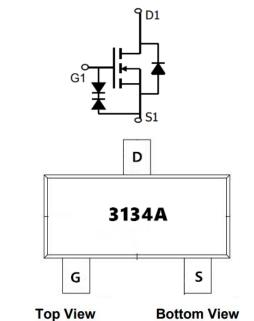
ESD=2KV HBM

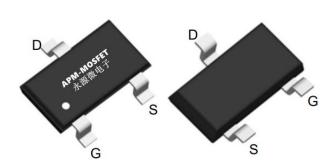
#### **Application**

Battery protection

Load switch

Uninterruptible power supply





**Package Marking and Ordering Information** 

Product ID	Pack	Marking	Qty(PCS)
AP3134AI	SOT23-3L	3134AI	3000

Absolute Maximum Ratings@T<sub>i</sub>=25°C(unless otherwise specified)

Symbol	Parameter	Max.	Units
VDSS	Drain-Source Voltage	20	V
VGSS	Gate-Source Voltage	±10	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	0.9	А
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	0.6	А
IDM	Pulsed Drain Current	3.6	A
P <sub>D</sub> @T <sub>C</sub> =25°C	Power Dissipation	0.23	W
TJ, TSTG	Operating and Storage Temperature Range	-55 to +150	°C
R <sub>θ</sub> JA	Thermal Resistance Junction-Ambient <sup>1</sup>	543	°C/W



# Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250µA	20	23	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V,	-	-	1	μΑ
IGSS	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±10V	-	-	±10	uA
VGS(th)	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	0.5	0.7	1.2	V
·	Static Drain-Source on-Resistance note2	V <sub>GS</sub> =4.5V, I <sub>D</sub> =0.5A	-	135	250	mΩ
RDS(on)		V <sub>GS</sub> =2.5V, I <sub>D</sub> =0.4A	-	195	280	
Ciss	Input Capacitance		-	60	-	pF
Coss	Output Capacitance	V <sub>DS</sub> =10V, V <sub>GS</sub> =0V, f=1.0MHz	-	22	-	pF
Crss	Reverse Transfer Capacitance	1-1.0WH12	-	12	-	pF
Qg	Total Gate Charge		-	1	-	nC
Qgs	Gate-Source Charge	$V_{DS}$ =10V, $I_{D}$ =0.9A, $V_{GS}$ =4.5V	-	0.28	-	nC
Qgd	Gate-Drain("Miller") Charge	VGS-4.5V	-	0.22	-	nC
td(on)	Turn-on Delay Time		-	2	-	ns
tr	Turn-on Rise Time	V <sub>DS</sub> =10V,	-	19	-	ns
td(off)	Turn-off Delay Time	$I_D$ =0.5A, $R_{GEN}$ =10Ω, $V_{GS}$ =4.5V	-	10	-	ns
t <sub>f</sub>	Turn-off Fall Time	VGS-4.5V	-	23	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	0.9	Α
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	3.6	Α
VSD	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =0.9A	-		1.2	V

#### Note:

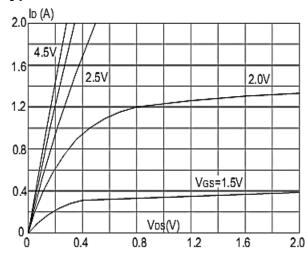
- 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3. The power dissipation is limited by 175°C junction temperature
- 4. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



2.0 [D (A)

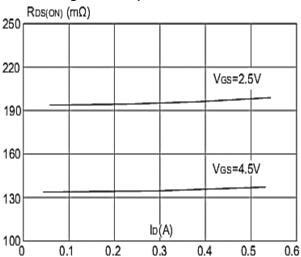
1.6

## **Typical Characteristics**



1.2 0.8 0.4 0 0 0.5 1 1.5 2.0 2.5 3.0

Figure1: Output Characteristics



**Figure 2: Typical Transfer Characteristics** 

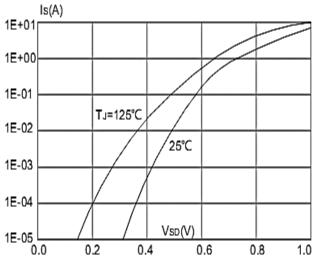
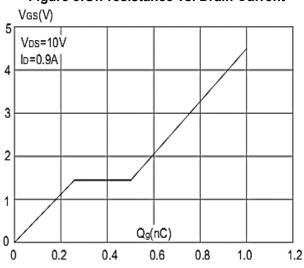
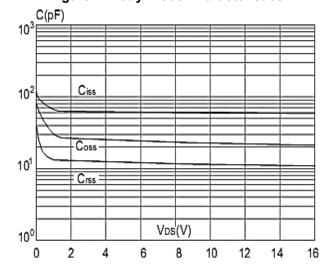


Figure 3:On-resistance vs. Drain Current



**Figure 4: Body Diode Characteristics** 



**Figure 5: Gate Charge Characteristics** 

Figure 6: Capacitance Characteristics





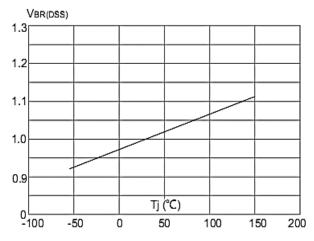


Figure 7: Normalized Breakdown Voltage vs Junction Temperature

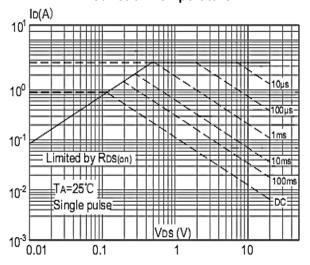


Figure 9: Maximum Safe Operating Area

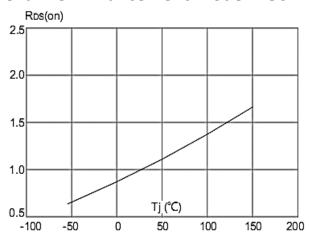


Figure 8: Normalized on Resistance vs.

Junction Temperature

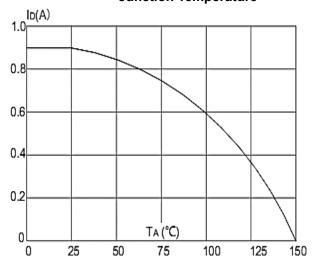


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

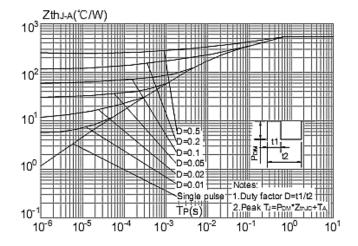
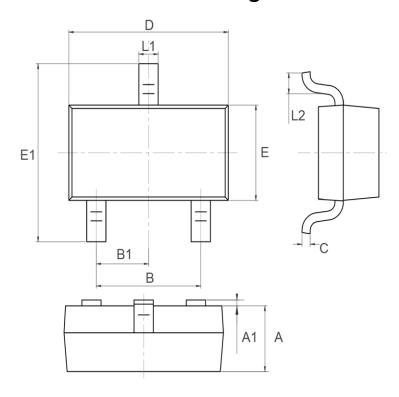


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien



# Package Mechanical Data-SOT23L-Single



C. mak al	Dim in mm			
Symbol	Min	Тур	Max	
А	0.9	1	1.1	
A1	0	0.05	0.1	
В	1.8	1.9	2	
B1	0.95TYP			
С	0.08	0.115	0.15	
D	2.8	2.9	3	
E	1.2	1.3	1.4	
E1	2.25	2.4	2.55	
L1	0.3	0.4	0.5	
L2	0.2	0.35	0.5	



# 20V N-Channel Enhancement Mode MOSFET Attention

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Edition	Date	Change
REV1.0	2020/7/15	Initial release

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